

Emmanuel Cadel

List of Publications by Year in descending order

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15
papers

565
citations

840776

11
h-index

996975

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all docs

15
docs citations

15
times ranked

846
citing authors

#	ARTICLE	IF	CITATIONS
1	Study of solute segregation behavior at carbide–ferrite interfaces in 16MND5 welds. <i>Journal of Nuclear Materials</i> , 2020, 542, 152531.	2.7	1
2	Investigation of solute segregation behavior using a correlative EBSD/TKD/APT methodology in a 16MND5 weld. <i>Journal of Nuclear Materials</i> , 2019, 523, 434-443.	2.7	22
3	Investigation of the dependence of phosphorus segregation on grain boundary structure in Fe-P-C alloy: Cross comparison between Atom Probe Tomography and Auger Electron Spectroscopy. <i>Applied Surface Science</i> , 2019, 463, 203-210.	6.1	20
4	Ultrathin PECVD epitaxial Si solar cells on glass via low-temperature transfer process. <i>Progress in Photovoltaics: Research and Applications</i> , 2016, 24, 1075-1084.	8.1	32
5	Nanometre-scale evidence for interfacial dissolution–reprecipitation control of silicate glass corrosion. <i>Nature Materials</i> , 2015, 14, 307-311.	27.5	227
6	Influence of boron clustering on the emitter quality of implanted silicon solar cells: an atom probe tomography study. <i>Progress in Photovoltaics: Research and Applications</i> , 2015, 23, 1724-1733.	8.1	11
7	Simultaneous Quantification of Indium and Nitrogen Concentration in InGaNs Using HAADF-STEM. <i>Microscopy and Microanalysis</i> , 2014, 20, 1740-1752.	0.4	20
8	Crystallographic Characterization of an Electroplated Zinc Coating Prone to Whiskers. <i>IEEE Transactions on Components, Packaging and Manufacturing Technology</i> , 2012, 2, 1928-1932.	2.5	6
9	Atomic scale investigation of silicon nanowires and nanoclusters. <i>Nanoscale Research Letters</i> , 2011, 6, 271.	5.7	12
10	Effect of die metallization layer ageing in the case of power semiconductor devices. <i>European Journal of Electrical Engineering</i> , 2011, 14, 569-585.	0.3	4
11	Depth resolution function of the laser assisted tomographic atom probe in the investigation of semiconductors. <i>Journal of Applied Physics</i> , 2009, 106, .	2.5	79
12	Phase Transformation and Segregation to Lattice Defects in Ni-Base Superalloys. <i>Microscopy and Microanalysis</i> , 2007, 13, 464-483.	0.4	81
13	Suzuki effect on {001} stacking faults in boron-doped FeAl intermetallics. <i>Scripta Materialia</i> , 2004, 51, 437-441.	5.2	16
14	Atomic Scale Investigation of Impurity Segregation to Crystal Defects. <i>Annual Review of Materials Research</i> , 2003, 33, 215-231.	9.3	20
15	Investigation of boron-enriched Cottrell atmospheres in FeAl on an atomic scale by three-dimensional atom-probe field-ion microscopy. <i>Philosophical Magazine Letters</i> , 2000, 80, 725-736.	1.2	14